

IEC 61850 User Feedback Task Force - Feature #5090

Mod inheritance when multiple root LD's (GrRef's) exist

09/21/2021 03:58 AM - Carlos Rodriguez del Castillo

Status:	Closed	Start date:	09/21/2021
Priority:	Normal	Due date:	12/07/2021
Assignee:	Carlos Rodriguez del Castillo	% Done:	100%
Category:	Standard clarification required	Estimated time:	0.00 hour
Target version:		To discuss in WG10:	No
ID:	9	Short Proposal:	Add clarification upon correlating multiple hierarchies
Source:	H30	Standard(s):	IEC 61850-7-1 Ed2.1
TF Unique ID:	9 # H30	Needs More Information:	
WG10 Proposal:		Assigned TF:	
Estimated Completion:			
Discuss in Upcoming Meeting:	No		
Description			
Need clarification on the inheritance of test mode when multiple root LD's (GrRef's) exist in a single physical IED.			

History

#1 - 12/07/2021 08:19 AM - Vladan Cvejic

- Due date changed from 01/21/2022 to 12/07/2021
- Status changed from New to Closed
- % Done changed from 0 to 100
- Discuss in Upcoming Meeting changed from Yes to No
- Short Proposal set to Add clarification upon correlating multiple hierarchies

According to discussion, there is no need for any additional clarification. It is clear that the hierarchies are independent as stated in 7-1 and 7-4.

No further clarification required - Closing.